



Reduction processes in Cu/SiO₂, Co/SiO₂, and CuCo/SiO₂ catalysts

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ABSTRACT

Cu/SiO₂, Co/SiO₂, and bimetallic CuCo/SiO₂ catalysts have been synthesized and their reduction behavior characterized by TPR, *in situ* XRD, and *in situ* XANES. In Cu/SiO₂, a two step reduction process, CuO → Cu₂O → Cu⁰, occurred. Two forms of the intermediate Cu₂O with different degrees of reducibility were observed. Addition of cobalt to Cu/SiO₂ resulted in formation of an amorphous fraction of CuO that was more easily reducible than crystalline CuO. Cobalt addition also prevented formation of the less reducible form of Cu₂O. Addition of copper to Co/SiO₂ increased the reducibility of Co₃O₄, and to greater extent of the intermediate CoO, which in the monometallic Co/SiO₂ was less readily reduced due to interaction with the support.

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1. Introduction

Catalysts based on copper and cobalt have been studied for hydrogenation of CO to mixtures of ethanol and higher alcohols. This reaction is thought to occur by a dual site mechanism: CO associatively adsorbed on one type of site is inserted into surface hydrocarbon species arising from CO dissociation on the other site [1,2]. Hydrogenation of the resulting intermediate yields the alcohol. The site pairs mainly responsible for alcohol synthesis are often proposed to be Cu⁰ and Co⁰ in close interaction or proximity [1,3,4], but have occasionally been identified as Co⁰/Co^{δ+} pairs, with copper maintaining this state of reduction [5]. In fact, the nature of the active centers may depend on the activation conditions applied to the catalyst [6]. Therefore, it is important to understand reduction processes in both copper–cobalt catalysts and their monometallic counterparts.

Bulk unsupported CuO normally reduces in a single step to Cu⁰, without formation of a Cu₂O intermediate [7,8]. Copper oxide becomes reducible at lower temperature when supported on silica than when unsupported, due to increased dispersion and greater reactivity toward H₂ [9–11]. Sometimes multiple peaks are observed during temperature programmed reduction (TPR) of Cu/SiO₂ catalysts. In such cases, some authors associate the lower temperature peak with reduction of a CuO phase of low crystallinity and small particle size, presumably forming Cu⁰ directly [11–14]. Others claim small CuO particles should interact with

SiO₂, hindering reduction [10]. Moreover, if the area ratio of these TPR peaks is ~1:1, then the possibility of a sequential reduction, CuO → Cu₂O → Cu, must also be considered.

Co/SiO₂ catalysts typically reduce in two steps: Co₃O₄ → CoO → Co⁰ [15–17]. The second step, in particular, is impeded by support interactions that become important when the particle size is small [15]. Divalent cobalt species show increasing difficulty of reduction in the following order: Co²⁺ with little support interaction, Co²⁺ having slightly stronger interaction with SiO₂, cobalt hydrosilicates, and cobalt silicate [16]. Cobalt silicate, which is favored by high-pH preparation conditions, shows a TPR maximum at about 900 °C [16].

TPR of unsupported, coprecipitated, air-calcined oxides of cobalt and copper shows that the presence of copper promotes the reduction of Co₃O₄ [18]. CuCo/SiO₂ catalysts usually show a single TPR peak at lower temperature than is typical for reduction of cobalt oxides [19–21]. Different authors have assumed a strong interaction between CuO and Co₃O₄ [18,19,21] or even formation of a Cu_xCo_{3–x}O₄ phase [18,20] to explain the promoting effect of copper on cobalt reduction.

Catalyst reduction pathways depend on preparation method, thermal treatment, and metal loading and can be quite complex even in monometallic systems. Addition of a second metal complicates the system even further. Therefore, a thorough characterization of the activation process is a prerequisite for understanding the nature of active species in each catalyst. The objective of this work is to apply complementary characterization techniques (TPR, *in situ* XRD, and *in situ* XANES) to study the effects of copper and cobalt upon each other during reduction of SiO₂-supported catalysts.

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2. Materials and methods

2.1. Catalyst preparation

Three catalysts were prepared by incipient wetness impregnation of SiO₂ (PQ Corporation) with an aqueous solution of Cu(NO₃)₂·2.5H₂O alone, Co(NO₃)₂·6H₂O alone, or both these salts together. The catalysts were dried overnight (17 h) at 100–105 °C. They were calcined in a tube furnace in stagnant air by ramping at 4 °C/min to 500 °C and maintaining that temperature for 2 h.

The designations and nominal compositions, on a post-reduction basis, of the three catalysts are as follows: (1) Cu/SiO₂, 3.5 wt% Cu; (2) Co/SiO₂, 3.5 wt% Co; and (3) CuCo/SiO₂, 3.5 wt% Cu, 3.5 wt% Co.

2.2. Composition and texture

The actual compositions of the calcined catalysts were determined by ICP-OES using a Perkin Elmer 2000 DV ICP-optical emission spectrometer.

Flow BET measurements were performed in an Altamira AMI-200 system. About 40 mg of calcined catalyst was pretreated in 30 sccm He at 150 °C for 30 min. N₂ concentrations of 10%, 20%, and 30% in a He carrier were used for the adsorption. BET surface area was calculated based on N₂ adsorption at liquid nitrogen temperature.

2.3. Temperature programmed reduction (TPR)

TPR experiments were carried out in an Altamira AMI-200 system. The catalyst (45 mg) was dried in 30 sccm He at 120 °C for 100 min. After cooling to room temperature, the catalyst was exposed to 30 sccm of 10% H₂/Ar flow as the temperature ramped at 10 °C/min to 750 °C. H₂ consumption was monitored by a thermal conductivity detector (TCD). Calibration of the TCD by TPR of Ag₂O enabled quantitative evaluation of H₂ consumption.

2.4. In situ X-ray diffraction (XRD)

XRD experiments were done at the Center for Nanophase Materials Sciences, Oak Ridge National Laboratory, Oak Ridge, TN. The catalyst sample was loaded into an Anton Paar XRK900 reaction chamber and exposed to 4% H₂/He flow. XRD patterns were recorded at selected temperatures by a PANalytical X'Pert Pro MPD diffractometer using Cu K α radiation. The scan speed was 0.030384°/s, and the step size was 0.017°.

Phase identification was carried out by the Search & Match feature of X'Pert HighScore Plus (v. 3.0) using the library provided by the Crystallography Open Database.

2.5. In situ X-ray absorption near edge structure (XANES)

XANES measurements were collected on the Double Crystal Monochromator (DCM) beamline at the J. Bennett Johnston, Sr., Center for Advanced Microstructures and Devices (CAMD), Baton Rouge, LA. About 20 mg of sample was mixed with 20 mg of amorphous SiO₂ and loaded into a Lytle cell. As a 10% H₂/Ar mixture flowed over the catalyst, the temperature was increased at 2 °C/min to 362 °C.

XANES spectra were collected at the Cu K-edge of CuCo/SiO₂ and the Co K-edge of Co/SiO₂ and CuCo/SiO₂. During the temperature ramp, scans were collected using the following parameters: 1 eV steps in the range –50 to –15 eV relative to the edge, 0.5 eV steps in the range –15 to 50 eV, and 1 eV steps in the range 50–100 eV. The integration time at each data point was 1 s. A foil reference of

Table 1

Catalyst surface areas, determined by flow BET, and compositions, determined by ICP-OES.

Catalyst	S_{BET} (m ² /g)	Composition (wt%)	
		Co	Cu
Cu/SiO ₂	261 ± 14	–	3.30 ± 0.06
Co/SiO ₂	268 ± 11	2.99 ± 0.15	–
CuCo/SiO ₂	251 ± 4	2.97 ± 0.02	3.18 ± 0.09

the element being measured was placed in the beam path beyond the sample and scanned in transmission mode.

Transmission data were processed and analyzed in the Athena (v. 0.8.061) component of the Iffeffit software [22]. First, the edge energy of the foil reference (taken as the maximum in the first derivative of its spectrum) was shifted to its literature value (8979 eV for Cu, 7709 eV for Co) [23]. Each simultaneously measured sample spectrum was calibrated according to that shift. The spectra were processed by deglitching and determination of the pre-edge line and normalization range. Next, each spectrum was analyzed by linear combination fitting (LCF) of its derivative to the derivative spectra of reference standards. The Cu standards included CuO, Cu₂O, and Cu⁰ foil. The Co standards included Co₃O₄, CoO, and Co⁰ foil. The model adopted for each fitting each spectrum was selected by a combinatorial approach, using all three standards and all possible combinations of two standards. Of the four possible fits, the one with the lowest χ^2_v value was chosen. Each fit was confined to the region of the derivative spectrum that showed clear peaks.

3. Results

3.1. Composition and texture

BET and ICP-OES results are listed in Table 1. The surface areas of all the catalysts, according to N₂ adsorption, are between 250 and 270 m²/g. The surface area of calcined SiO₂ is 279 m²/g.

3.2. TPR

TPR profiles of the three catalysts are shown in Fig. 1. Cu/SiO₂ exhibits a main peak at 220 °C, with a high temperature shoulder and another small feature at 300 °C. The Co/SiO₂ profile contains a broad area of hydrogen consumption, spanning from 220 °C to 600 °C and apparently consisting of several overlapping reduction

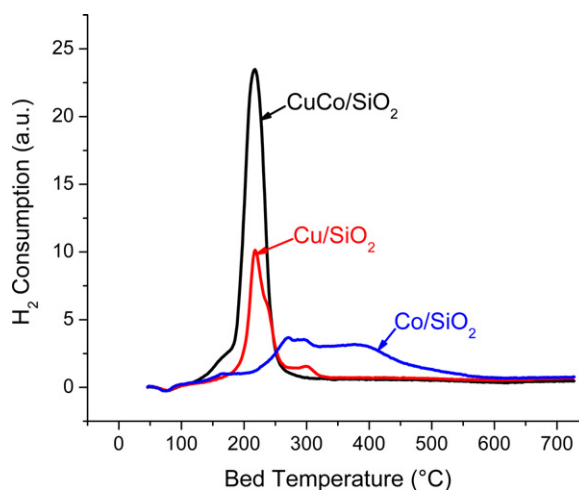


Fig. 1. TPR profiles in 10% H₂/Ar, ramping at 10 °C/min.

Table 2
Quantitative H₂ consumption during TPR.

Catalyst	H ₂ consumption (mmol/g)	Expected H ₂ consumption ^a (mmol/g)
Cu/SiO ₂	0.65 ± 0.10	0.52
Co/SiO ₂	0.76 ± 0.09	0.68
CuCo/SiO ₂	1.50 ± 0.23	1.17

^a Assuming complete conversion of CuO and Co₃O₄ to Cu⁰ and Co⁰, respectively.

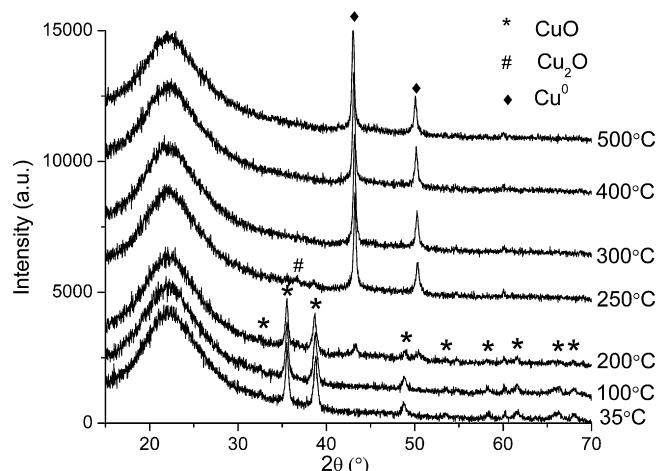


Fig. 2. XRD patterns of Cu/SiO₂ during reduction in 4% H₂/He at the indicated temperatures.

bands. Like that of Cu/SiO₂, the CuCo/SiO₂ TPR shows a prominent peak at 220 °C, but its shoulder is on the low temperature side.

Quantities of hydrogen consumed by each catalyst are listed in Table 2. In each case, the catalyst consumes sufficient hydrogen to reduce CuO, when present, to Cu⁰ and Co₃O₄, when present, to Co⁰. In addition, the hydrogen consumption by CuCo/SiO₂ is near the sum of the total uptakes by Cu/SiO₂ and Co/SiO₂.

3.3. In situ XRD

The XRD patterns of Cu/SiO₂ during isothermal hydrogen reduction at selected temperatures are shown in Fig. 2. This catalyst initially contains CuO, as expected. With increasing temperature, the crystalline phases in Cu/SiO₂ transform as follows. At 200 °C, a small amount of Cu⁰ appears. At 250 °C, CuO almost disappears, and Cu⁰ is the dominant phase. A minor peak at $2\theta = 36.6^\circ$ and $d = 2.45$ suggests also the presence of a small amount of Cu₂O [14,24,25]. By 300 °C, Cu⁰ is the only remaining phase detected by XRD.

The XRD patterns of Co/SiO₂ during reduction (Fig. 3) show that Co₃O₄ is the starting crystalline phase, which transforms to CoO by 300 °C. At 400 °C, CoO has begun converting to a cubic Co⁰ phase, but this process is complete only after an extended time at 600 °C.

CuCo/SiO₂ initially contains crystalline CuO and Co₃O₄ (Fig. 4). At 200 °C, metallic phases have begun to appear. Intermediates such as Cu₂O and CoO may also be present at this stage, though interference from other peaks hinders this determination. By 300 °C, only metallic crystalline phases remain.

The sizes of crystallites in the three catalysts were determined by the Scherrer method with correction for instrumental broadening. Table 3 shows the changing crystallite sizes with increasing temperature.

CuO crystallites are slightly larger in Cu/SiO₂ (21–26 nm) than in CuCo/SiO₂ (19–20 nm). In addition, at room temperature, the area of the CuO (1 1 1) peak (not shown) is 50% less in CuCo/SiO₂ than in Cu/SiO₂. The copper metal loading (from ICP) is only about 4%

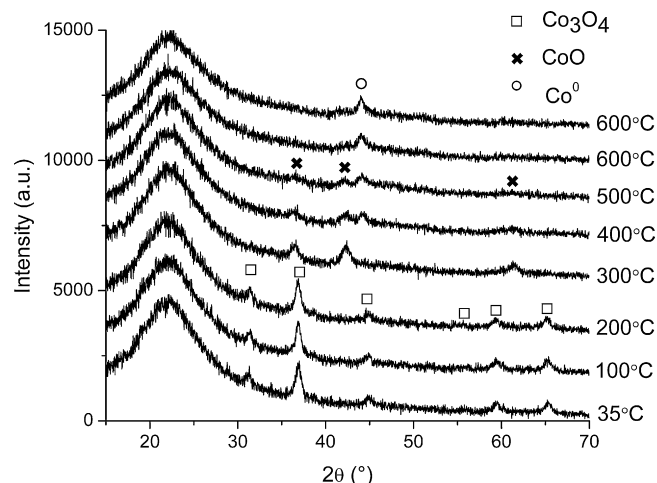


Fig. 3. XRD patterns of Co/SiO₂ during reduction in 4% H₂/He at the indicated temperatures. A second scan was collected at 600 °C immediately after the first.

lower in CuCo/SiO₂ than in Cu/SiO₂. Thus, the bimetallic catalyst contains both crystalline and noncrystalline CuO.

When Cu⁰ appears in Cu/SiO₂, crystallites initially have an average diameter of 22.4 nm (200 °C), but enlarge to 57.1 nm at 250 °C and 62–66 nm at higher temperatures. These sizes, from Table 3, were calculated based on the Cu⁰ (1 1 1) peak. If instead the Scherrer formula is applied to the Cu⁰ (2 0 0) peak, the Cu⁰ crystallite diameter is 11.6 nm at 200 °C, 32.6 nm at 250 °C, and 44–47 nm at 300–500 °C. If the (1 1 1) plane is assumed parallel to the support, the different dimensions obtained from different peaks suggest a flattened particle shape [26].

Co₃O₄ crystallite sizes fall into the same range (11–16 nm) in Co/SiO₂ and CuCo/SiO₂. However, at room temperature, the area of the Co₃O₄ (3 1 1) peak is 30% higher in CuCo/SiO₂ than in Co/SiO₂, whereas the cobalt metal loading is about the same in both catalysts. This suggests that more crystalline, and less amorphous, Co₃O₄ exists in CuCo/SiO₂ than in Co/SiO₂ at room temperature.

In Co/SiO₂, the intermediate CoO phase has a crystallite size of 7–12 nm. When Co⁰ crystallites appear at 400–600 °C, they are similar in size. The final Co⁰ crystallite size is close to 75% of the starting Co₃O₄ crystallite size, which would be expected on the basis of the molar volumes of Co⁰ and Co₃O₄ [17,27]. Co⁰ crystallites on Co/SiO₂ do not exhibit the marked sintering that Cu⁰ crystallites do on Cu/SiO₂.

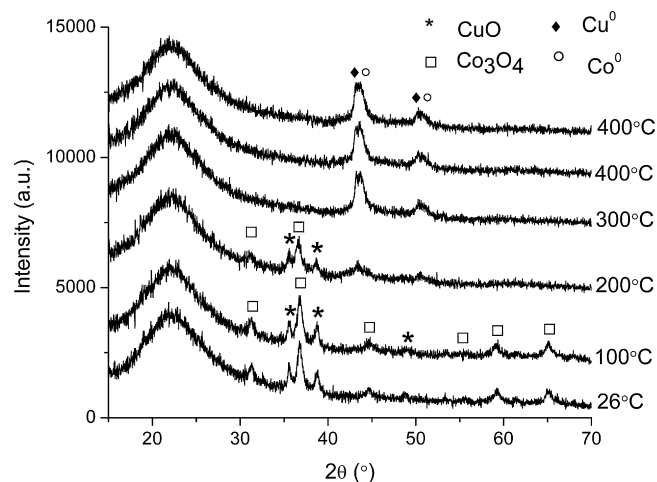


Fig. 4. XRD patterns of CuCo/SiO₂ during reduction in 4% H₂/He at the indicated temperatures. A second scan was collected at 400 °C immediately after the first.

Table 3

Crystallite size (nm), determined by the Scherrer method with correction for instrumental broadening.

Temperature (°C)	Cu/SiO ₂		Co/SiO ₂			CuCo/SiO ₂	
	CuO ^a	Cu ^{0a}	Co ₃ O ₄ ^a	CoO ^a	Co ^{0a}	CuO ^a	Co ₃ O ₄ ^a
35 (26) ^b	24.8	–	12.7	–	–	19.6	15.2
100	21.6	–	15.0	–	–	20.0	13.7
200	25.5	22.4	13.7	–	–	19.0	11.0
250	–	57.1	–	–	–	–	–
300	–	62.1	–	8.6	–	–	–
400	–	65.7	–	7.5	10.0	–	–
500	–	65.6	–	11.5	7.6	–	–
600	–	–	–	–	8.8, 10.3 ^c	–	–

^a The crystallite size calculations are based on the following peaks: CuO (1 1 1), Cu⁰ (1 1 1), Co₃O₄ (3 1 1), CoO (2 0 0), and Co⁰ (1 1 1).^b Room temperature measurements were collected at 35 °C on Cu/SiO₂ and Co/SiO₂ and at 26 °C on CuCo/SiO₂.^c From back-to-back measurements at 600 °C.

The overlapping of the diffraction peaks of Cu⁰ and Co⁰ in CuCo/SiO₂ prevents accurate determination of their crystallite size. Overlapping or intermediate peaks can arise from intermediate lattice spacing between the spacings of pure Cu⁰ and Co⁰, due to alloying of the metals [28,29]. To address the question of possible alloying in CuCo/SiO₂, the diffraction patterns of Cu/SiO₂, Co/SiO₂, and CuCo/SiO₂ at 400 °C are compared in Fig. 5. The formation of CuCo alloy cannot be ruled out from this figure, although in general Cu⁰ has limited solubility in Co⁰ [6] and would be expected to segregate to the surface of such an alloy to lower the surface free energy [27].

3.4. In situ XANES

The XANES spectra and LCF results at the Co K-edge of Co/SiO₂, the Co K-edge of CuCo/SiO₂, and the Cu K-edge of CuCo/SiO₂ during temperature programmed reduction are shown in Figs. 6–8, respectively. The XANES spectra of cobalt and copper reference compounds are shown in Fig. 9. Sample LCFs from each *in situ* experiment are shown in Fig. 10.

Initially, Co₃O₄ is the only cobalt phase present in Co/SiO₂ (Fig. 6). At about 280 °C, the white line region of the spectrum begins to assume the more rounded shape of the CoO standard, which is confirmed by the appearance of CoO in the LCF profile. However, as Co₃O₄ reduces, the fit becomes imperfect in the white line region as shown in Fig. 10. Probably, Co₃O₄ reduces via CoO species that have varying degrees of interaction with the support. Electron deficiencies due to such interactions can result in enhanced white line intensities that cannot be perfectly modeled by reference spectra of bulk compounds [30]. Consequently, the full extent of Co₃O₄

conversion may not be completely captured by the LCF results in Fig. 6. Nevertheless, the spectra clearly show that appreciable Co₃O₄ reduction occurs by 280 °C. Furthermore, a small shoulder begins to develop at the absorption edge at 358 °C, denoting the first appearance of Co⁰.

Fig. 7 shows the Co K-edge spectra and LCF results on CuCo/SiO₂. The low-temperature scans confirm that Co₃O₄ is the starting

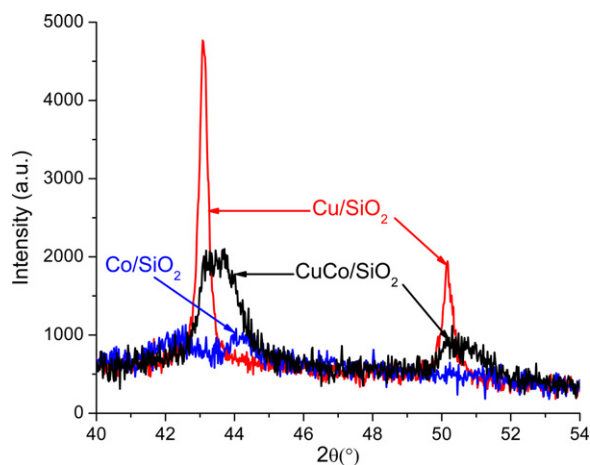


Fig. 5. XRD patterns of Cu/SiO₂, Co/SiO₂, and CuCo/SiO₂ during reduction in 4% H₂/He at 400 °C.

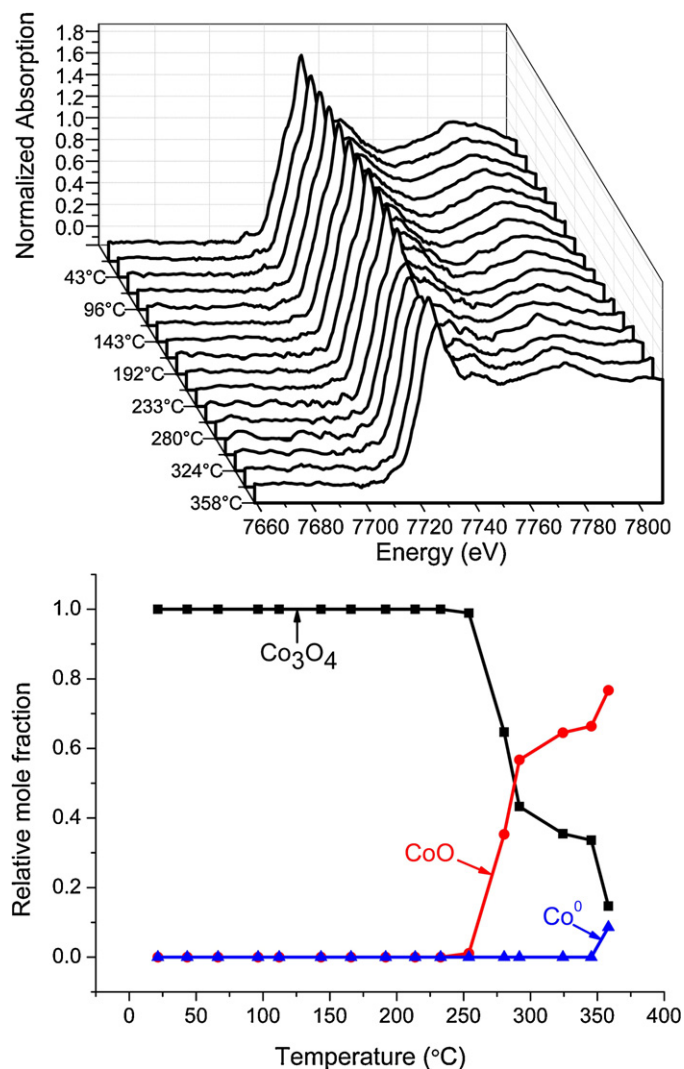


Fig. 6. Top: XANES spectra at the Co K-edge of Co/SiO₂ during temperature ramping at 2 °C/min in 10% H₂/Ar. Bottom: Composition of cobalt phases in Co/SiO₂, from LCF, as a function of temperature. Non-cobalt phases are excluded from the mole fractions.

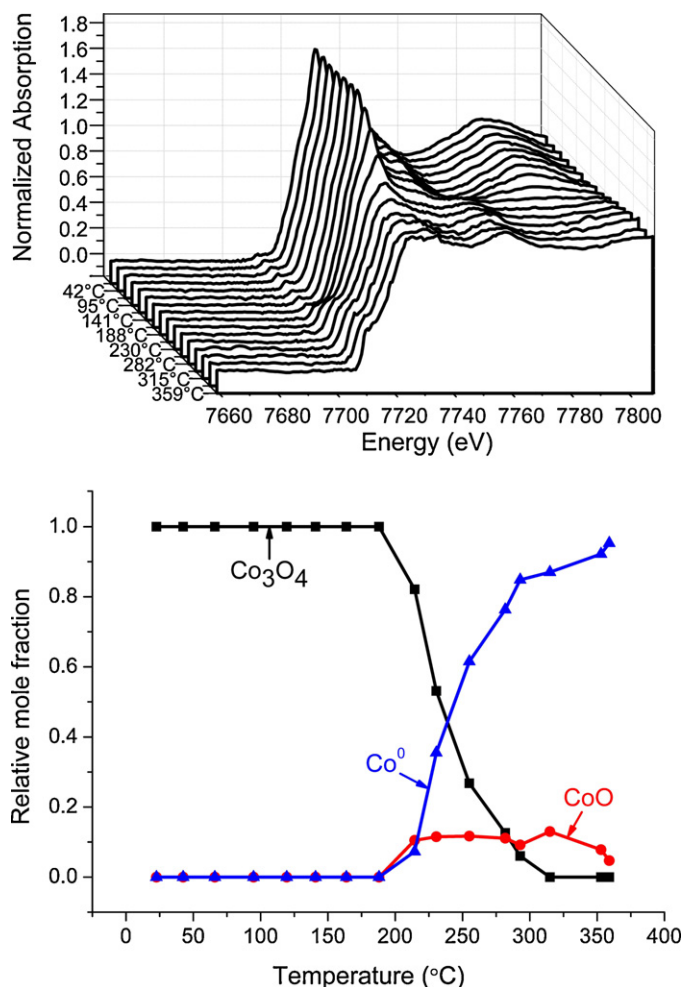


Fig. 7. Top: XANES spectra at the Co K-edge of CuCo/SiO₂ during temperature ramping at 2 °C/min in 10% H₂/Ar. Bottom: Composition of cobalt phases in CuCo/SiO₂, from LCF, as a function of temperature. Non-cobalt phases are excluded from the mole fractions.

cobalt phase in this catalyst. Conversion to CoO begins at about 215 °C, 65 °C lower than for the monometallic Co/SiO₂ catalyst. This is also accompanied by a decrease in the white line intensity and growth of a shoulder at the edge, corresponding to the simultaneous appearance of Co⁰ at the same temperature.

Fig. 8 shows the Cu K-edge spectra and LCF results on CuCo/SiO₂. When compared to the Cu reference standards in Fig. 9, the spectra up to 140 °C match that of CuO. In the early stages of reduction, CuO is converted first to Cu₂O. At about 230 °C, Cu⁰ appears as well. By 300 °C, conversion to Cu⁰ is complete.

4. Discussion

After isothermal reduction at 400 °C, Cu/SiO₂ would be expected to contain Cu⁰, Co/SiO₂ to contain Co⁰ and CoO, and CuCo/SiO₂ to contain a mixture of Cu⁰ and Co⁰. Thus, the reduction temperature can be manipulated in order to produce catalysts containing the desired species, whether Co⁰/Cu⁰ or Co⁰/Co²⁺.

4.1. Effect of Co addition to Cu/SiO₂

The low temperature shoulder in the TPR (Fig. 1) of CuCo/SiO₂ can be identified with the help of XRD and XANES results. From peak fitting of the TPR profile, the shoulder arises from a band at about 170 °C that accounts for 12.5% of the total hydrogen

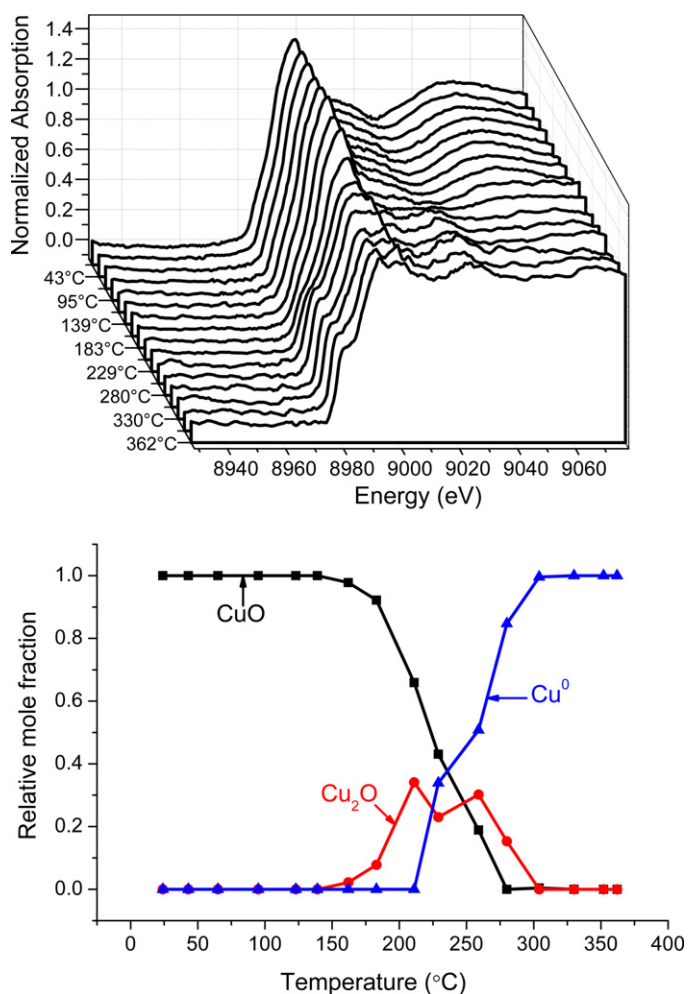


Fig. 8. Top: XANES spectra at the Cu K-edge of CuCo/SiO₂ during temperature ramping at 2 °C/min in 10% H₂/Ar. Bottom: Composition of copper phases in CuCo/SiO₂, from LCF, as a function of temperature. Non-copper phases are excluded from the mole fractions.

consumption by this catalyst. In the room temperature XRD patterns, comparison of the areas of the CuO (1 1 1) peak of Cu/SiO₂ and of CuCo/SiO₂ shows that this phase is more crystalline in Cu/SiO₂. Assuming that CuO in Cu/SiO₂ is fully crystalline, an estimated 50% of the CuO in CuCo/SiO₂ is noncrystalline. Thus, the main TPR peak at 220 °C (observed for both catalysts) involves reduction of crystalline CuO, and the shoulder at 170 °C (visible only in CuCo/SiO₂) corresponds to reduction of noncrystalline CuO. From XANES (Fig. 8), it is clear that CuO in CuCo/SiO₂ begins reducing to Cu₂O before 200 °C, before the appearance of metallic Cu, and before any reduction of Co₃O₄. Accordingly, the earlier conclusion can be extended to say the shoulder at 170 °C relates to reduction of noncrystalline CuO to Cu₂O. This point can be further corroborated by calculating the percentage of total H₂ consumption needed to reduce noncrystalline CuO (that is, 50% of total CuO in CuCo/SiO₂) to Cu₂O. This value comes to 10.7%, compared to 12.5% obtained by peak fitting. The slight discrepancy between the two values might have been introduced during profile fitting of the TPR and XRD patterns.

An alternative explanation for the decrease in crystalline CuO and increase in crystalline Co₃O₄ observed by XRD in CuCo/SiO₂ relative to the monometallic catalysts could be formation of a mixed oxide. A spinel-type oxide, with incorporated Cu, would be difficult to distinguish from Co₃O₄ by XRD [31,32]. However, the Cu_xCo_{3-x}O₄ phase shows low thermal stability, especially at

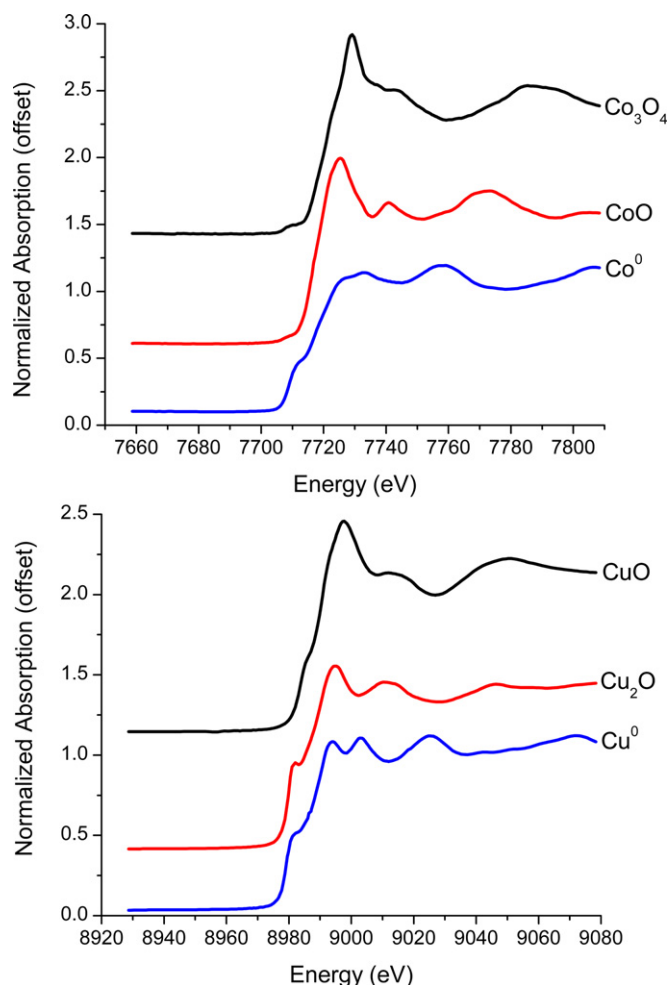


Fig. 9. Top: Co K-edge XANES spectra of reference standards (Co_3O_4 , CoO , and Co^0) used in LCF of cobalt phases. Bottom: Cu K-edge XANES spectra of reference standards (CuO , Cu_2O , and Cu^0) used in LCF of copper phases.

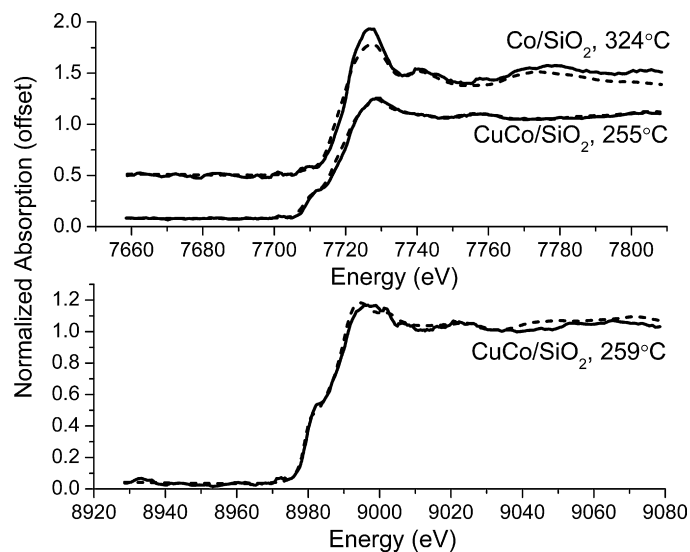


Fig. 10. Sample LCFs of Co K-edge spectra (top), including Co/SiO_2 at 324 °C and CuCo/SiO_2 at 255 °C, and a Cu K-edge spectrum (bottom) of CuCo/SiO_2 at 259 °C.

Cu/Co ratios as high as the one used in this work, and would be expected to decompose during the calcination at 500 °C [31]. Furthermore, XANES analysis does not support the formation of a copper–cobalt mixed metal oxide in the catalyst as-prepared or during reduction. For example, the XANES lineshapes from Cu^{2+} in CuO and in the octahedral sites of a spinel would be expected to differ markedly, by analogy to results obtained on CuO and CuFe_2O_4 (Fig. 3 of [33]). These reasons support the idea that the decrease in CuO diffraction peaks is due to creation of an amorphous fraction of CuO , not incorporation of Cu into the spinel phase.

The Cu/SiO_2 TPR profile (Fig. 1) has shoulders on the high, rather than low, temperature side. Peak fitting reveals that the main peak at 220 °C, already assigned to reduction of crystalline CuO , has an area approximately equal to the sum of the areas of the high temperature shoulder (240 °C) and small peak at 300 °C. From the stoichiometry of H_2 consumption for a stepwise reduction, this suggests that the main peak corresponds to reduction of CuO to Cu_2O , and the secondary peaks represent reduction of Cu_2O to Cu^0 . From XRD (Fig. 2), residual crystalline Cu_2O is observed at 250 °C and converts to Cu metal during isothermal treatment at 300 °C. This confirms that Cu_2O is an intermediate during reduction of Cu/SiO_2 .

The separation of Cu_2O reduction into two TPR peaks suggests that a fraction of the intermediate Cu_2O (about 26% of it) is especially difficult to reduce to Cu metal. It is not obvious why this should be so, but the type of Cu_2O that reduces with relative difficulty at 300 °C is not observed in CuCo/SiO_2 .

4.2. Effect of Cu addition to Co/SiO_2

The reduction of Co/SiO_2 occurs over a wide temperature range, which implies the existence of many reducible species in varying degrees of interaction with the support [16]. The amplified white line of the Co K-edge spectra of reducing Co/SiO_2 suggests that the Co^{2+} species, in particular, are more electron deficient than in bulk CoO . In fact, the XANES spectra of CoO and Co_2SiO_4 are quite similar [17], the main difference being a more intense white line in the spectrum of the latter. Nevertheless, the formation of Co_2SiO_4 , which reduces at temperatures greater than 800 °C [16,17], does not seem to occur on Co/SiO_2 , which is completely reduced at 600 °C. According to the XRD results (Fig. 3), CoO itself is difficult to reduce on Co/SiO_2 and is observed across a wide temperature span, 300–500 °C. The strength of interaction of Co^{2+} with SiO_2 seems to lie somewhere between bulk unsupported CoO and Co_2SiO_4 .

Co_3O_4 in CuCo/SiO_2 reduces simultaneously with crystalline CuO , at a temperature about 65 °C lower than the corresponding transformation in Co/SiO_2 . The reduction of Co^{2+} is very efficiently promoted by copper. According to TPR and XRD, this process is complete by 300 °C on CuCo/SiO_2 , whereas it continues up to 600 °C on Co/SiO_2 . XANES also shows that the CoO intermediate is reduced almost as fast as it can be produced on CuCo/SiO_2 , in marked contrast to the situation on Co/SiO_2 . This indicates that an interaction between copper and cobalt phases exists, and it has a stronger effect on Co^{2+} reducibility than the cobalt–silica interaction, which would tend to maintain cobalt in an oxidized state.

5. Conclusions

CuO and Co_3O_4 reduce via two step processes— $\text{CuO} \rightarrow \text{Cu}_2\text{O} \rightarrow \text{Cu}^0$ and $\text{Co}_3\text{O}_4 \rightarrow \text{CoO} \rightarrow \text{Co}^0$, respectively, on SiO_2 -supported monometallic and bimetallic catalysts. The effects of cobalt addition to a Cu/SiO_2 catalyst are (1) an increase in the dispersion and amorphous content of CuO , (2) creation of a more easily reducible (to Cu_2O) fraction of CuO , due to its higher dispersion, and (3) elimination of a type of Cu_2O that is relatively

difficult to reduce. The main effect of copper addition to a Co/SiO₂ catalyst is to increase the reducibility of cobalt oxides, especially of CoO.

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